Applicant(s)/Patent Under Application/Control No. Reexamination 10/730,264 EGAWA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 ARMANDO RODRIGUEZ 2828 **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-US-Κ US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP 02281670 11-1990 **JAPAN** KIMIYA, HITOSHI Ν 0 Ρ Q R s Ţ **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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